

FIG. 1(A)

FORMATION OF INSULATING LAYER 101a

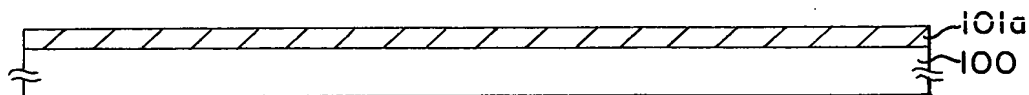


FIG. 1(B)

SEQUENTIAL FORMATION OF INSULATING LAYER 101b AND SEMICONDUCTOR FILM

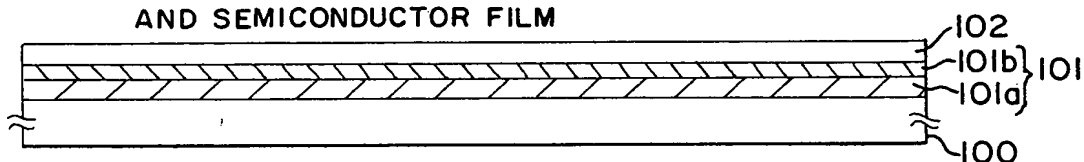


FIG. 1(C)

CRYSTALLIZATION

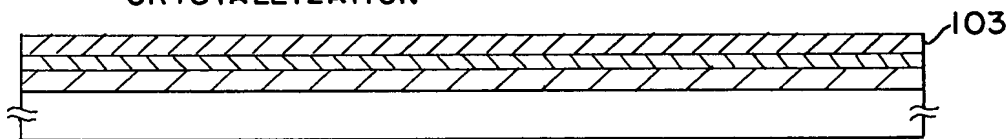


FIG. 1(D)

FORMATION OF ACTIVE LAYER AND GATE INSULATING FILM

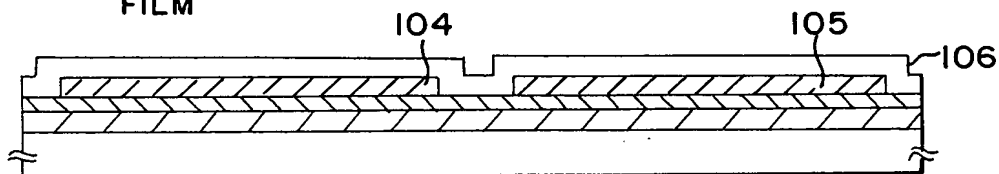


FIG. 1(E)

FORMATION OF GATE WIRING

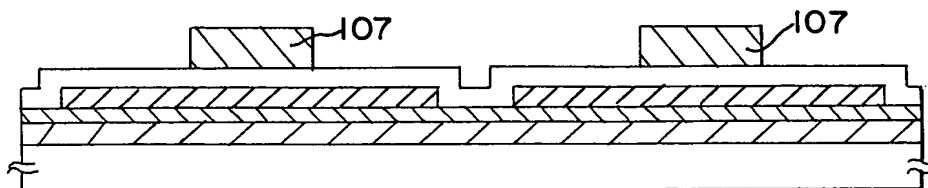


FIG.2(A)

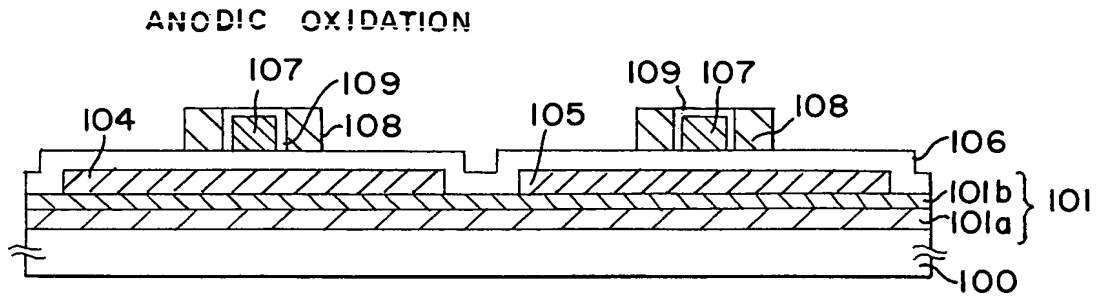


FIG.2(B)

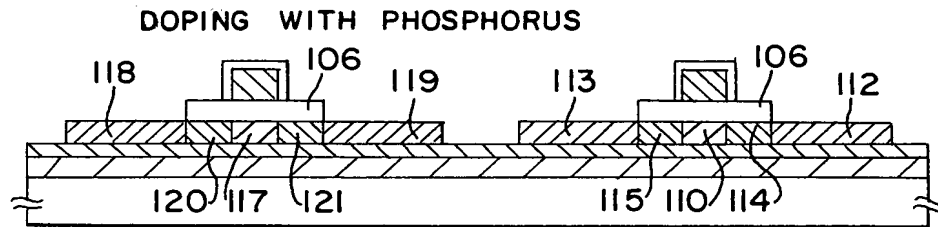


FIG.2(C)

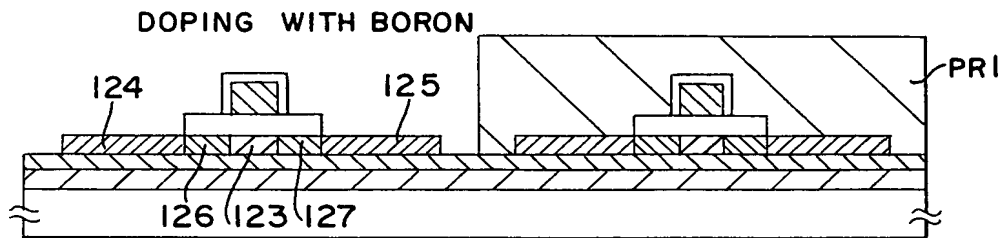
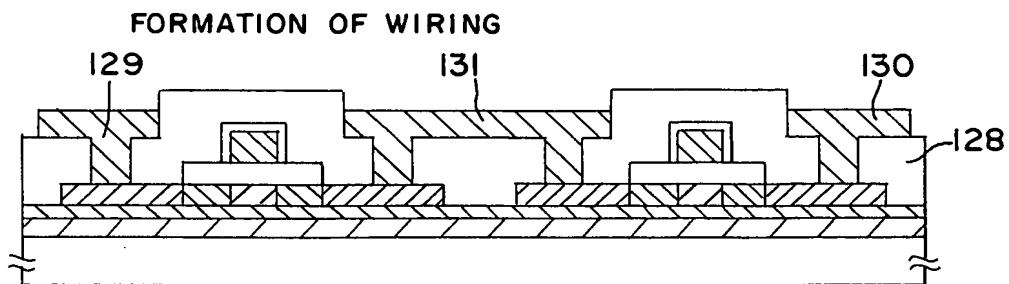


FIG.2(D)



P-CHANNEL TYPE

N-CHANNEL TYPE



FIG. 3

FLOW RATE OF RAW MATERIAL GAS	Si H 4	SUBSTRATE 1	SUBSTRATE 2	SUBSTRATE 3	SUBSTRATE 4
		4	400	10	15
	N 2 O			20	20
	N H 3		0	100	200
HEAT TREATMENT		CONDUCTED	NO	NO	NO
COMPOSITION RATIO (ATOMIC %)	N	7.0		24.0	44.1
	O	59.5		26.5	6.0
	Si	32.0		33.0	34.4
	H	1.5		16.5	15.5
REFRACTIVE INDEX		1.4566		1.7468	1.7975

FILM FORMING CONDITIONS AND PHYSICAL PROPERTIES
OF INSULATING LAYER (SILICON OXIDE NITRIDE LAYER) 101a

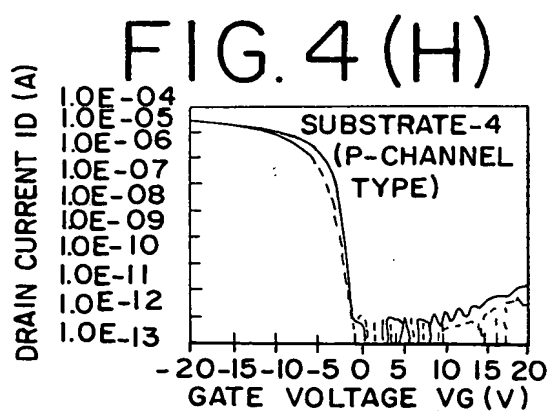
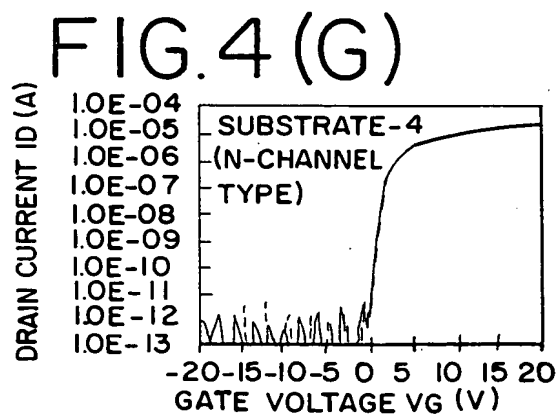
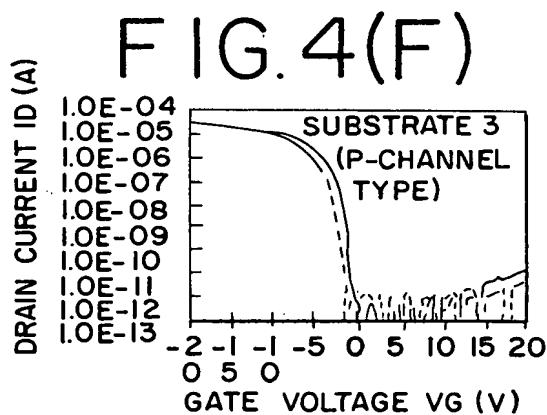
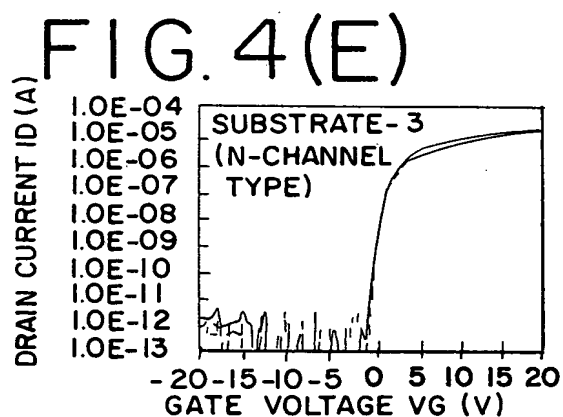
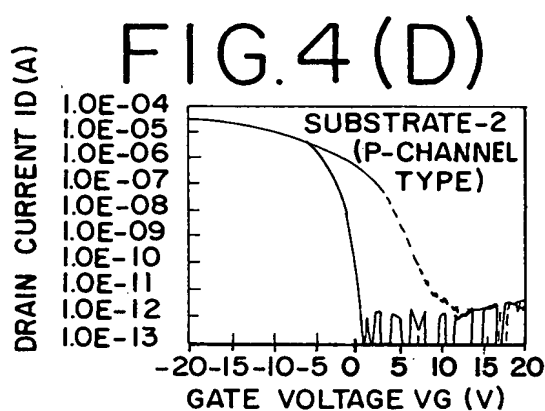
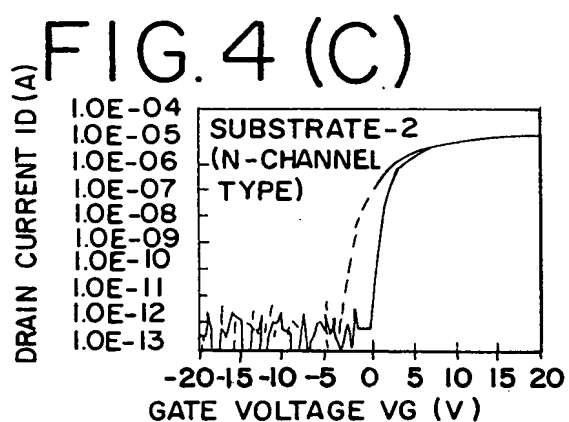
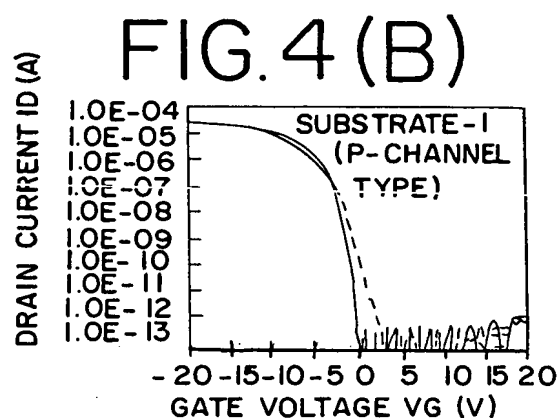
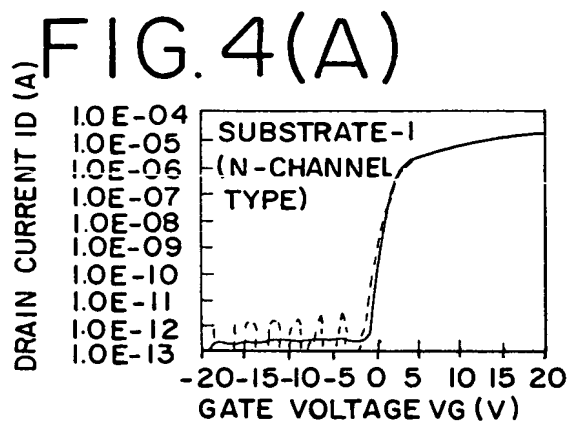


FIG. 5A

▨ N-CHANNEL TYPE (L/W=5.6/7.5 μ m)
▨ P-CHANNEL TYPE (L/W=5.6/7.5 μ m)

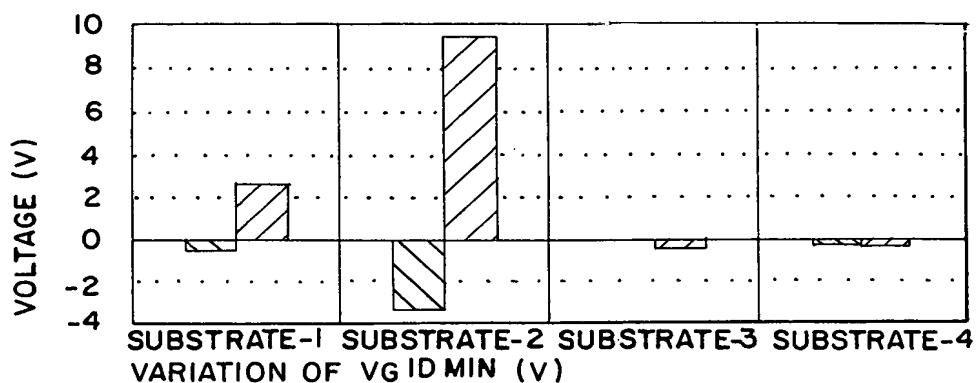


FIG. 5B

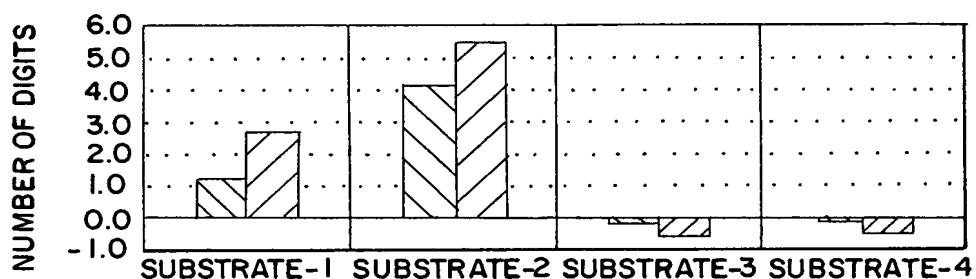


FIG. 5C

CHANGE OF NUMBER OF DIGITS OF 1 CUT

※ STRESS CONDITIONS

150°C, 1 HOUR, V_G : 20V (N-CHANNEL TYPE), -20V (P-CHANNEL TYPE),
 $V_D = V_S = 0V$

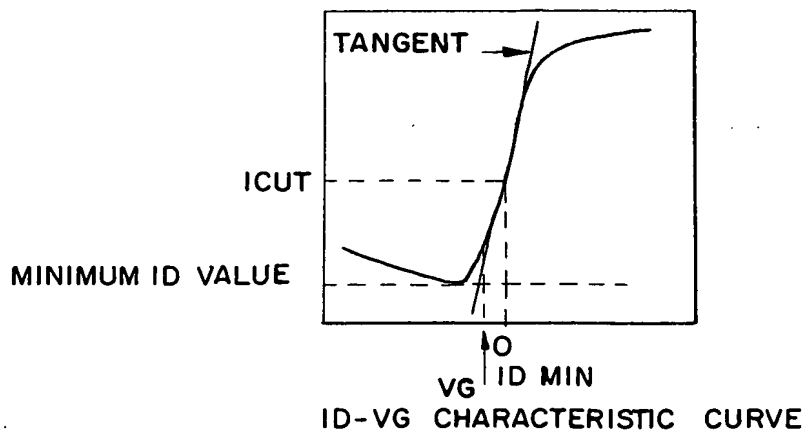


FIG.6

DRIVER CIRCUIT (CMOS CIRCUIT)

PIXEL MATRIX CIRCUIT

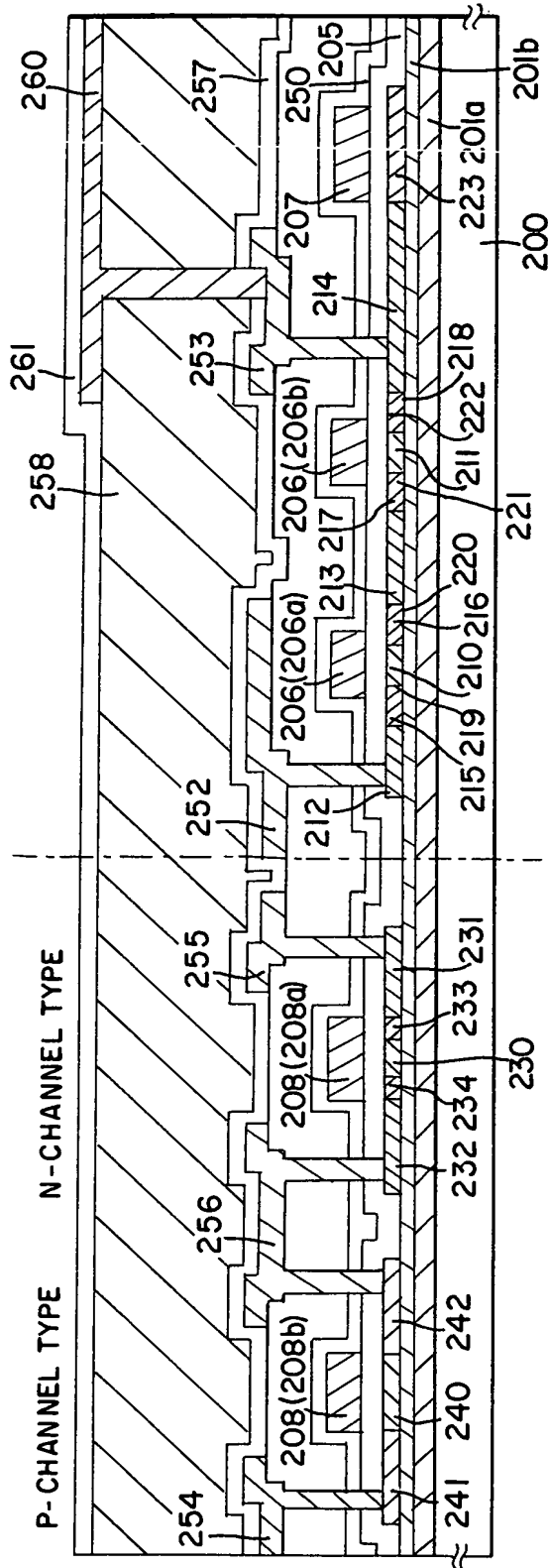


FIG. 7(A)

FORMATION OF UNDERLYING FILM, ACTIVE LAYER AND GATE INSULATING FILM

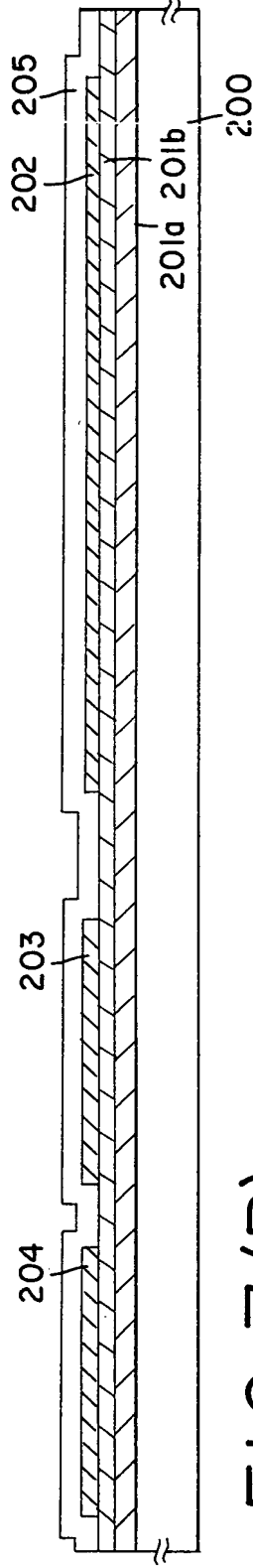


FIG. 7(B)

DOPING PROCESS OF PHOSPHORUS (FORMATION OF n⁺-TYPE REGION)

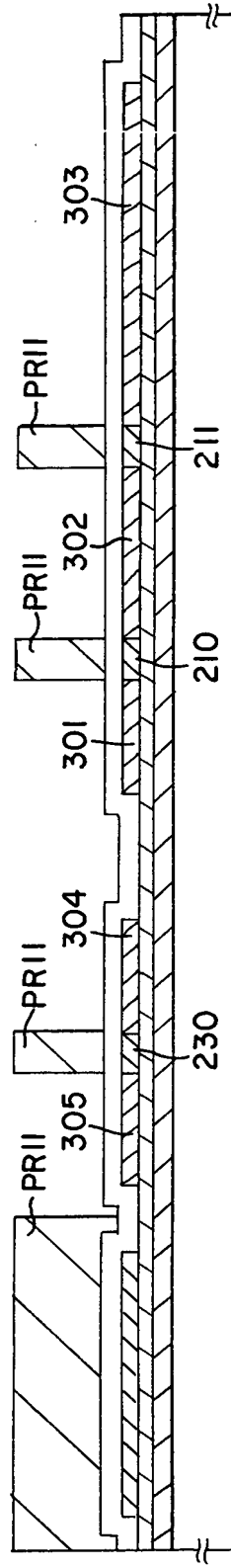


FIG. 7(C)

FORMATION OF CONDUCTIVE FILM

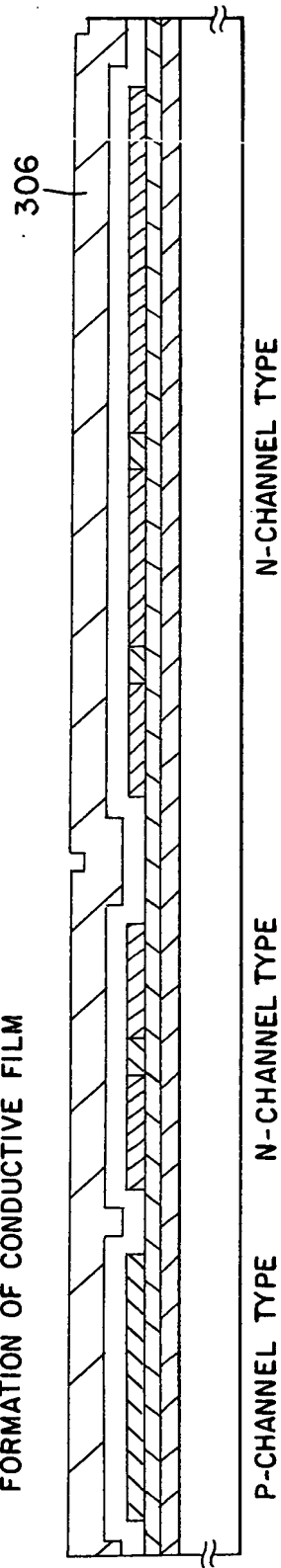


FIG.8(A)

DOPING WITH BORON (FORMATION OF P⁺-TYPE REGION)

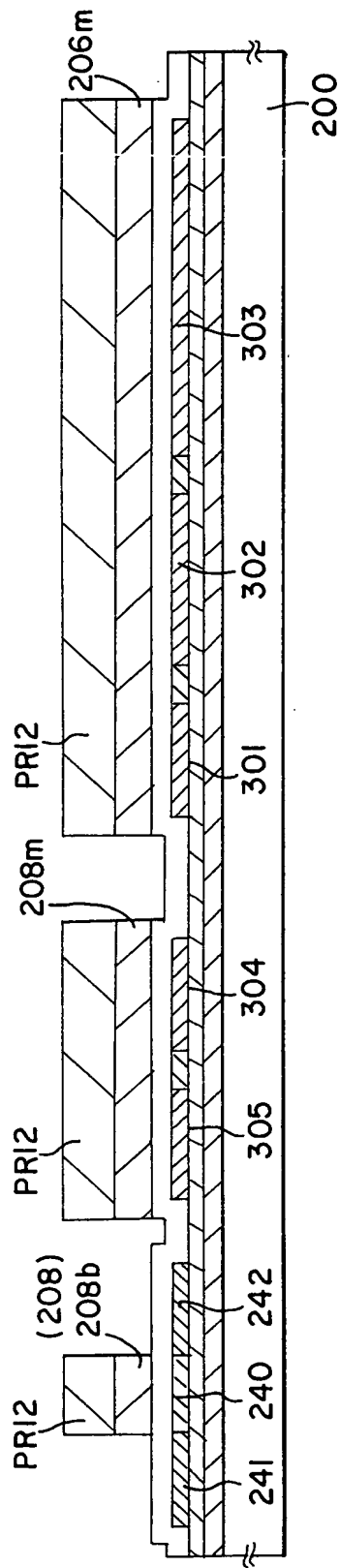
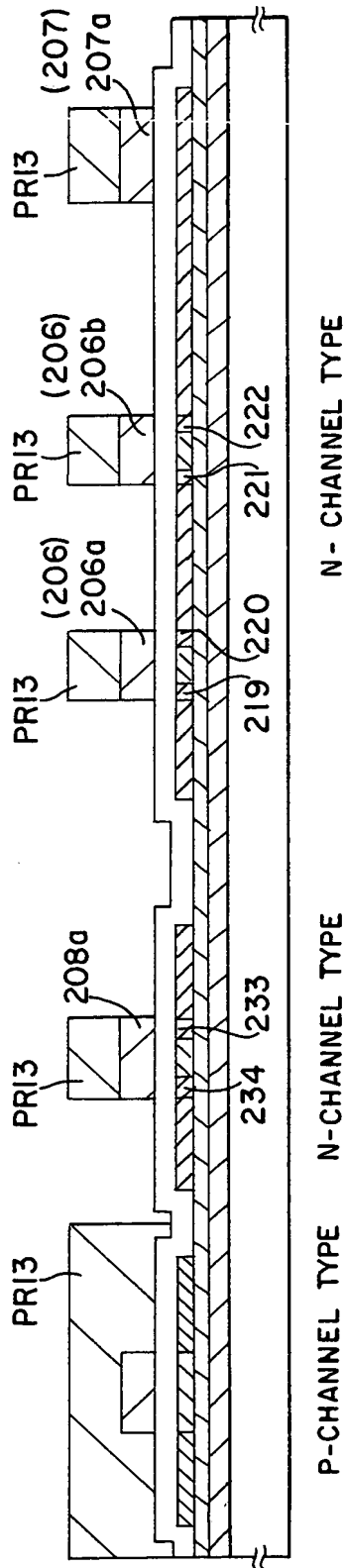


FIG.8(B)

FORMATION OF WIRING



P-CHANNEL TYPE

N-CHANNEL TYPE

FIG. 9(A)

DOPING WITH PHOSPHORUS (FORMATION OF n^+ -TYPE REGION)

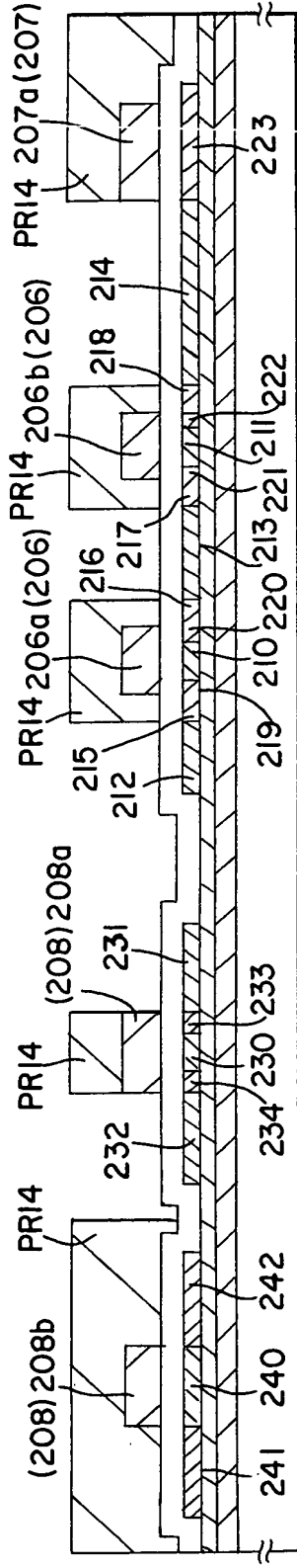


FIG. 9(B)

FORMATION OF WIRING AND ELECTRODE

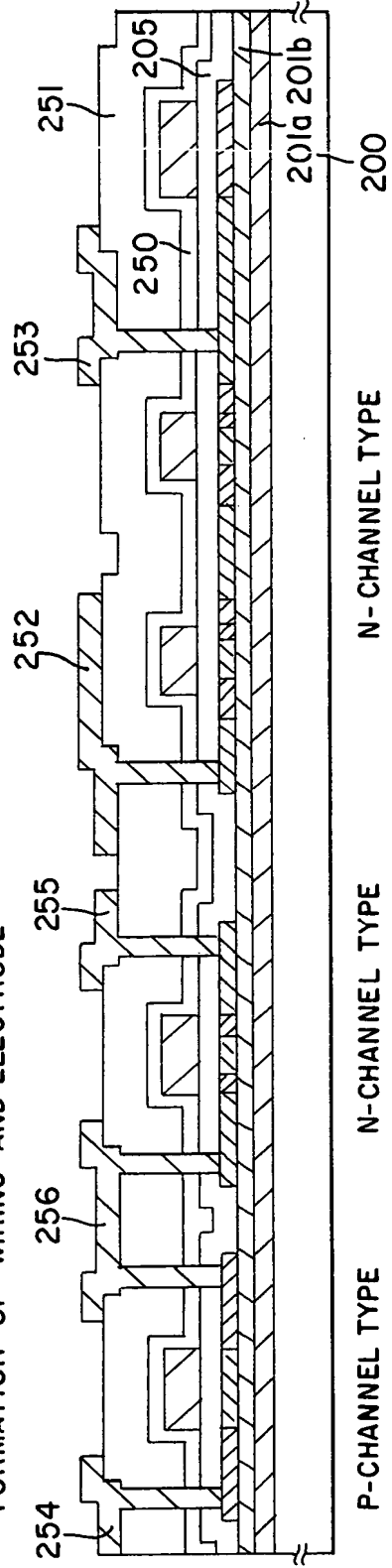
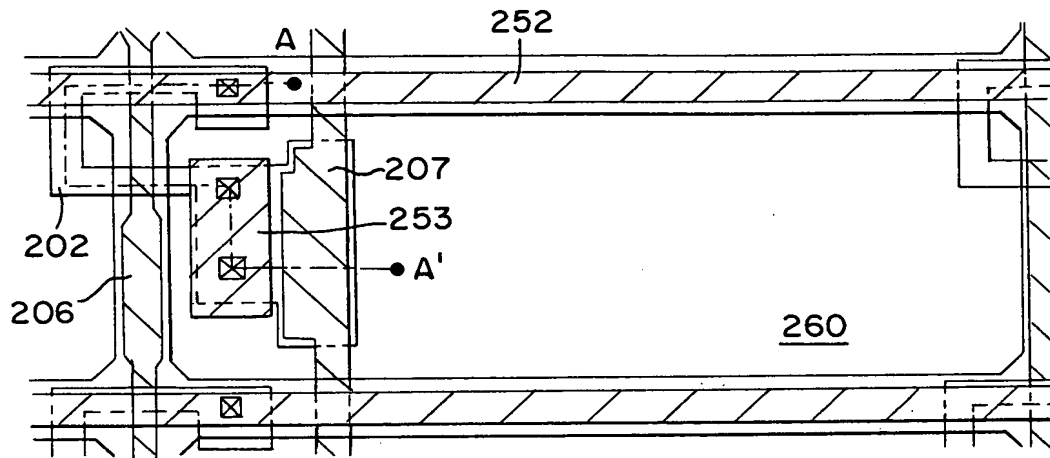


FIG. 10



PLAN VIEW OF PIXEL MATRIX CIRCUIT

FIG. 11

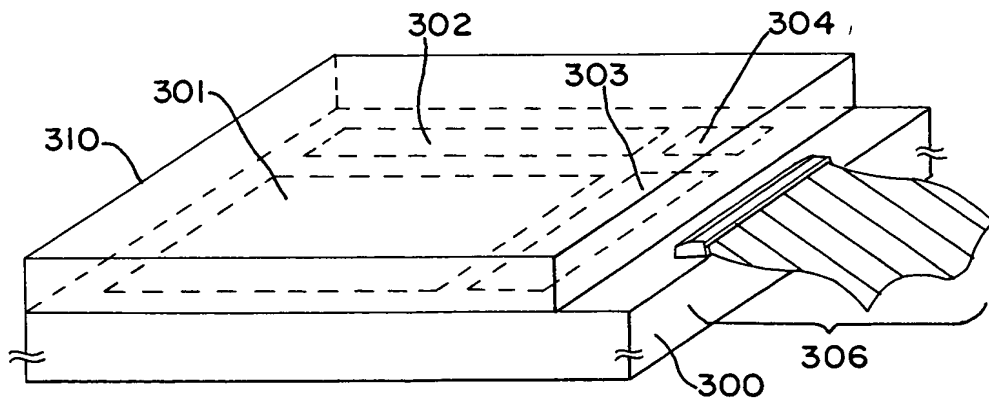


FIG. 12(A)

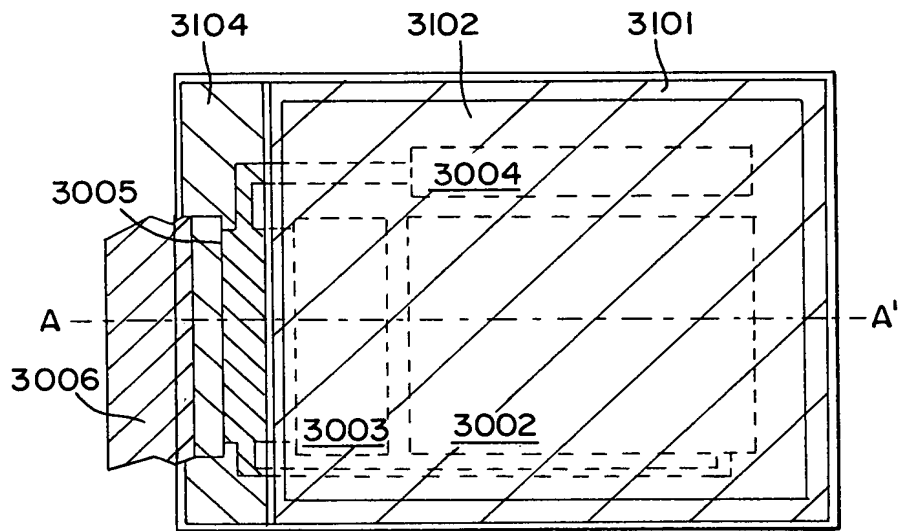


FIG. 12(B)

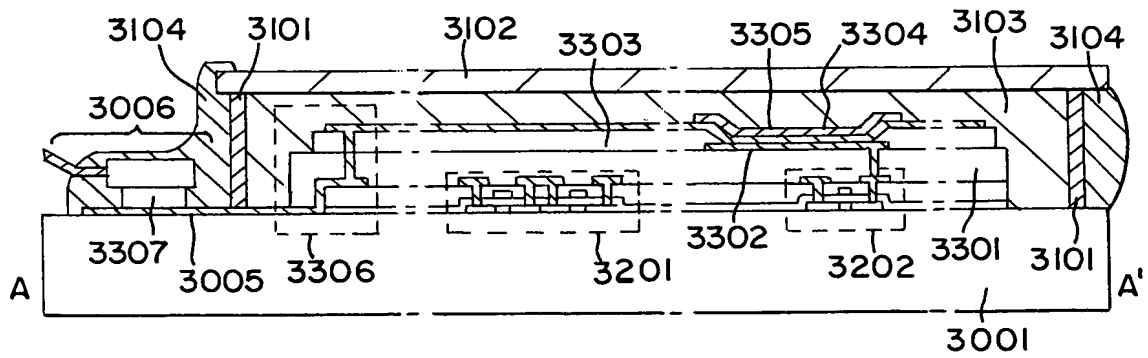


FIG. 13(A)

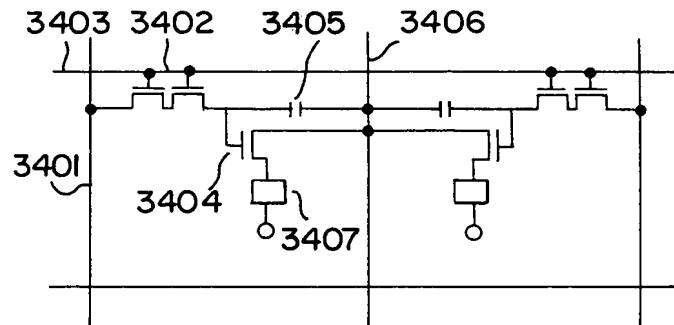


FIG. 13(B)

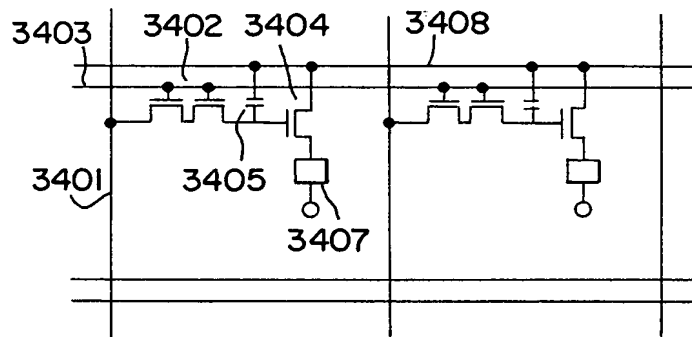


FIG. 13(C)

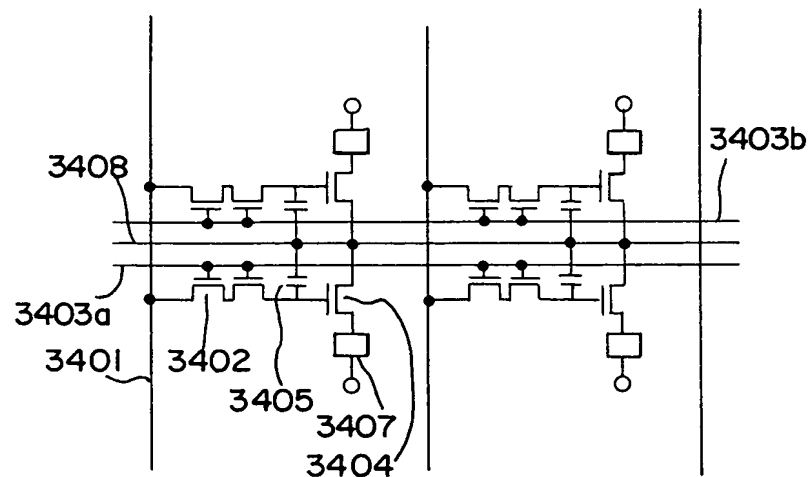


FIG. 14(A)

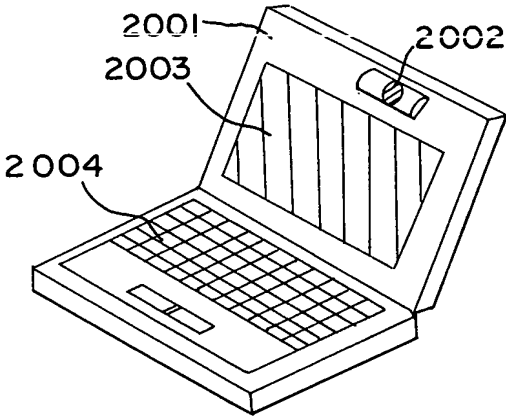


FIG. 14(B)

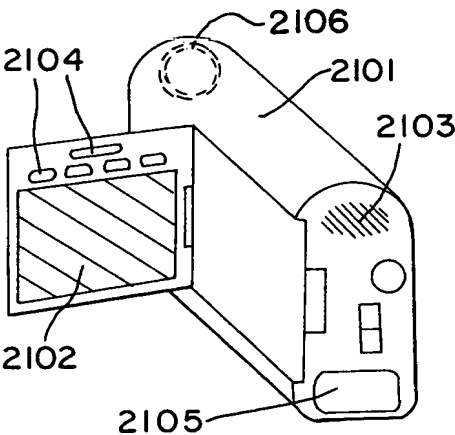


FIG. 14(C)

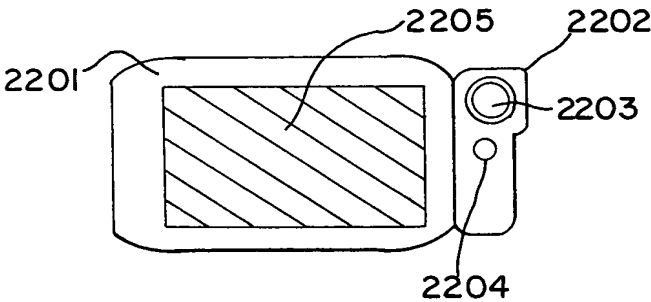


FIG. 14(D)

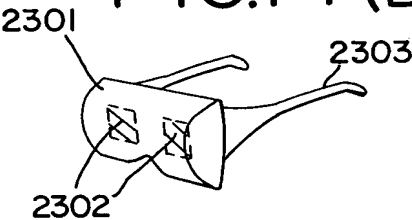


FIG. 14(E)

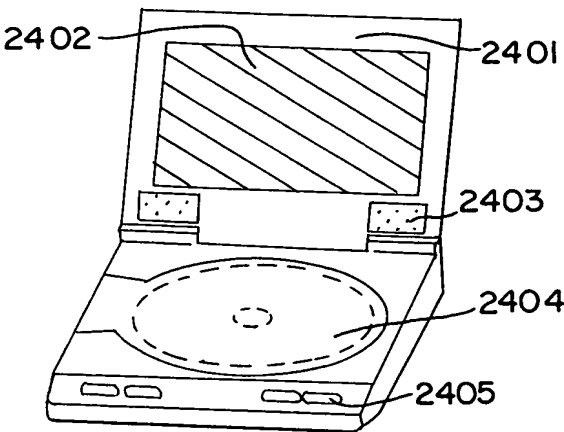


FIG. 14(F)

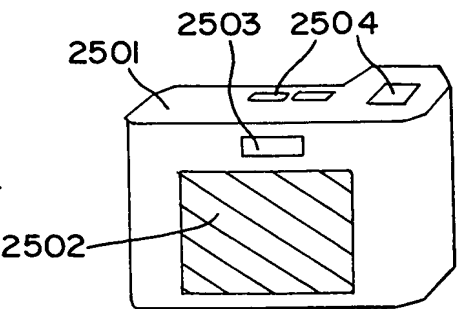


FIG. 15(A)

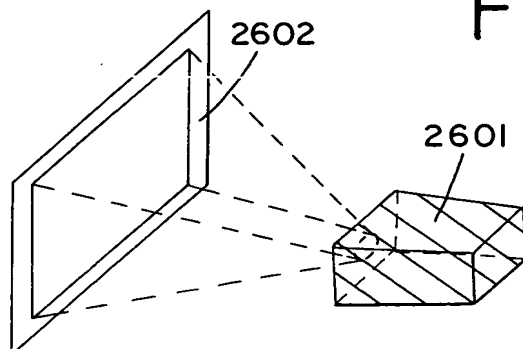


FIG. 15(B)

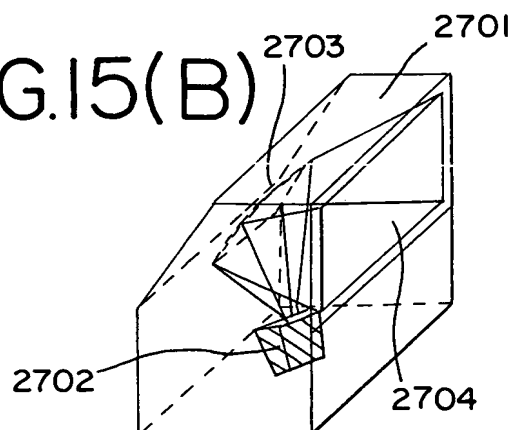


FIG. 15(C) PROJECTION UNIT (THREE-LENS TYPE)

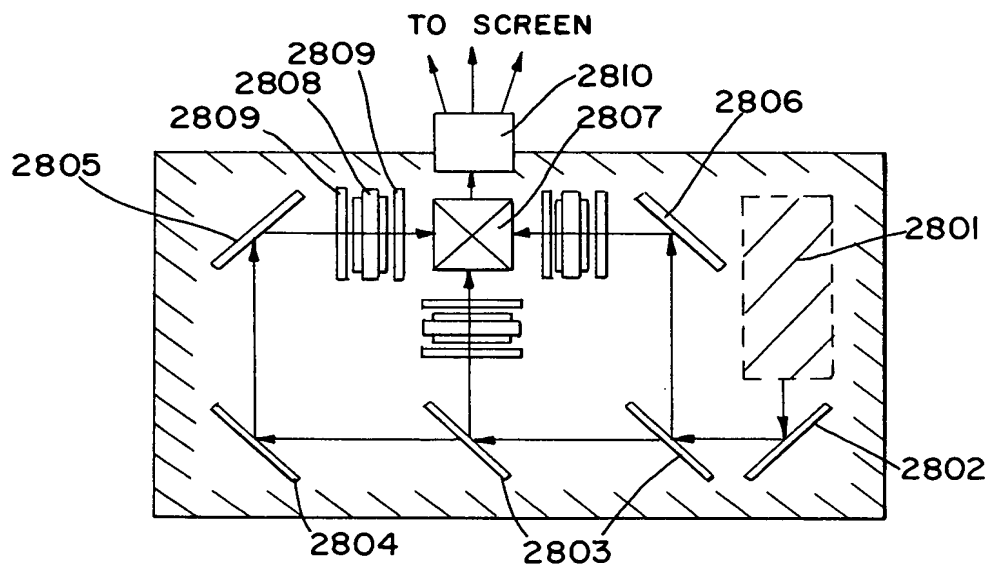


FIG. 15(D)

LIGHT SOURCE
OPTICAL SYSTEM

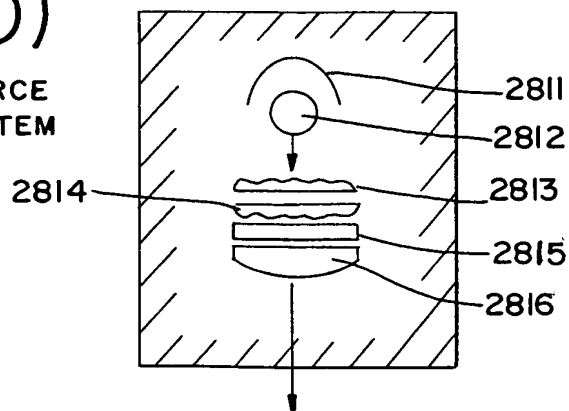


FIG. 16(A)

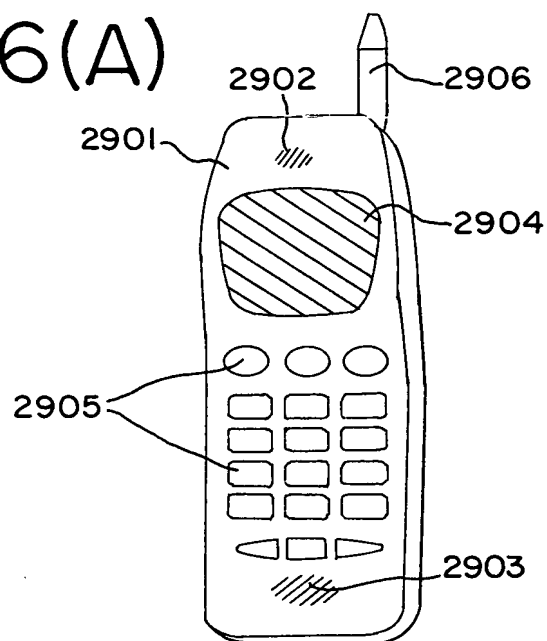


FIG. 16(B)

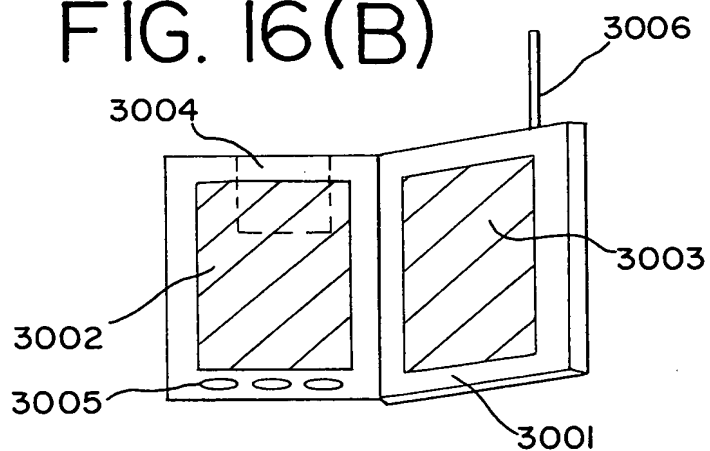


FIG. 16(C)

